

YIR: Memory

Speaker:

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Abstract

In the Memory YIR, I will present highlights from key recent papers specifically focused on reliability topics. Evolutionary memory technologies will be covered along with few papers from Emerging Memory areas. Since memory systems are increasingly becoming complex, there is significant focus in the community to understand not only component-level reliability challenges but at the system and product-levels as well. Therefore, I will focus on couple of key papers in these areas in addition to those at the device-level.